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HOUSING FOR TEST AND MEASUREMENT **INSTRUMENTS**

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(57)**CLAIM**

The ornamental design of a housing for test and measurement instruments, as shown and described.

DESCRIPTION

The ornamental design disclosed in this application is for a housing for test and measurement instruments, such as oscilloscopes, logic analyzers, waveform generators, and the like.

FIG. 1 is a perspective view of a housing for test and measurement instruments;

FIG. 2 is a front elevation view of the housing for test and measurement instruments;

FIG. 3 is a left side elevation view of the housing for test and measurement instruments;

FIG. 4 is a right side elevation view of the housing for test and measurement instruments;

FIG. 5 is a top plan view of the housing for test and measurement instruments;

FIG. 6 is a bottom plan view of the housing for test and measurement instruments; and,

FIG. 7 is a rear elevation view of the housing for test and measurement instruments.

1 Claim, 6 Drawing Sheets















